

LAB SCHEDULE

Name of the dept. : ECE

class : II – I - ECE-B

Lab name : ELECTRONIC DEVICES AND CIRCUITS LAB

year: 2014-15

LIST OF EXPERIMENTS

Frequency measurement using CRO.

2.PN Junction diode characteristics A. Forward bias B. Reverse bias.(cut-in voltage & Resistance calculations)

3.Zener diode characteristics and Zener as a regulator

4. Transistor CB characteristics (Input and Output) & h Parameter calculations

5. Transistor CE characteristics (Input and Output) & h Parameter calculations

6. Rectifier without filters (Full wave & Half wave)

7. Rectifier with filters (Full wave & Half wave)

8. JFET characteristics

9. SCR characteristics

10. UJT characteristics

Sl. No	Date & Session	Ex.1	Ex.2	Ex.3	Ex.4	Ex.5	Ex.6	Ex.7	Ex.8	Ex.9	Ex.10
1	1-9-14-(A.N)	DEMO ON EXPERIMENTS									
2	4-9-14 (F.N)	DEMO ON EXPERIMENTS									
3	19-9-14	B1/ B6	B2/ B7	B3/ B8	B4/ B9	B5/ B10					
4	26-9-14	B11/ B16	B12/ B17	B13/B 18	B14/ B19	B15/ B20					
5	07-11-14	B2/ B7	B3/ B8	B4/ B9	B5/ B10	B1/ B6					
6	21-11-14	B12/ B17	B13/ B18	B14/ B19	B15/ B20	B11/ B16					
7	28-11-14	B3/ B8	B4/ B9	B5/ B10	B1/ B6	B2/ B7					
8	12-12-14	B13/ B18	B14/ B19	B15/ B20	B11/ B16	B12/ B17					
9	19-12-14	B4/ B9	B5/ B10	B1/ B6	B2/ B7	B3/ B8					
10	26-12-14	B14/ B19	B15/ B20	B11/ B16	B12/ B17	B13/ B18					
11	04-09-14	B5/ B10	B1/ B6	B2/ B7	B3/ B8	B4/ B9					
12	11-09-14	B15/ B20	B11/ B16	B12/B 17	B13/B 18	B14/ B19					
13	25-09-14						B1/ B6	B2/ B7	B3/ B8	B4/ B9	B5/ B10
14	06-11-14						B11/ B16	B12/B 17	B13/B 18	B14/ B19	B15/ B20
15	13-11-14						B2/ B7	B3/ B8	B4/ B9	B5/ B10	B1/ B6
16	20-11-14						B12/ B17	B13/B 18	B14/ B19	B15/ B20	B11/ B16
17	24-11-14						B3/ B4/	B4/ B5/	B5/ B1/	B1/ B2/	B2/

							B8	B9	B10	B6	B7
18	1-12-14						B13/ B18	B14/ B19	B15/ B20	B11/ B16	B12/ B17
19	27-11-14						B4/ B9	B5/ B10	B1/ B6	B2/ B7	B3/ B8
20	8-12-14						B14/ B19	B15/ B20	B11/ B16	B12/ B17	B13/ B18
21	04-12-14						B5/ B10	B1/ B6	B2/ B7	B3/ B8	B4/ B9
22	15-12-14						B15/ B20	B11/ B16	B12/B 17	B13/B 18	B14/ B19
21	11-12-14	B1-B10 BACKLOG & REPEATETION									
22	22-12-14	B11-B20 BACKLOG & REPEATETION									
21	18-12-14	B1-B10 Internal exam									
22	29-12-14						B1-B10 internal exam				

Note: Session Indicates 3 (or) 4 Periods

B1 to B10 are batches and each batch contains 3 to 4 members